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-jim	AA	Re 34,908	9/5/00	Wyles, et a	al	250	208.1				
	AB	4,249,122	2/3/81	Widlar		353	313				
7.	AC	4,463,383	7/31/84	Sonoda,et	al	358	212				
100	AD	4,466,018	8/14/84	Sonoda, et		358	213				
in	ΑE	4,676,761	6/30/87	Poujois		445	_3 3				
in	AF	4,794,247	12/27/88	Stineman,	et al	250	214A				
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m	AH	5,083,016	1/21/92	Wyles, et		250	2081				
1	ΑI	5,345,266	9/6/94	Denyer, et		348	300				
~ K	AJ	5,296,696	3/22/94	Uno, M.		250	20811				
<i>∞</i>	AK	5,471,515	11/28/95	Fossum, et al		377	60				
Jin	AL	5,576,763	11/19/96	Ackland, et al		348	308	ŀ			
~~	AM	5,541,402	7/30/96	Ackland, et al		250	208,1				
<i>میر</i>	AN	5,587,596	12/24/96	Chi, et al		257	233				
in	AO	5,608,243	3/4/97	Chi, et al		25)	244	-			
in	AP	5,055,667	10/08/91	Sayag		250	208,1				
35	AQ	5,128,534	7/7/92	Wyles, et al		250	208.1				
	AR	5,146,302	9/8/92	Kumada		357	24				
	AS	5,382,977	1/17/95	Kozlowski, et al		348	300				
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,	AU	5,665,959	9/9/97	Fossum, e		438 250	208.1				
m	AV	5,929,434	7/27/99	Kozlowski,			214 A				
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